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### T5724 - ADVANTEST CORPORATION

... A **flash BIST tester**, capable of simultaneous testing for an extremely large number of devices. The T5724 is a **flash BIST tester** for wafer probe applications. ...

[www.advantest.co.jp/products/ate/t5724/en-index.shtml](http://www.advantest.co.jp/products/ate/t5724/en-index.shtml) - 24k - Jun 8, 2004 - [Cached](#) - [Similar pages](#)

### Press Release - ADVANTEST CORPORATION

... Advantest Corporation (TSE: 6587, NYSE: **ATE**) today announced ... increase in capacity over the previous model **tester**. ... in front-end test costs for **flash BIST** memory ...

[www.advantest.co.jp/news/press-2003/20031204a/en-index.shtml](http://www.advantest.co.jp/news/press-2003/20031204a/en-index.shtml) - 21k - Jun 8, 2004 - [Cached](#) - [Similar pages](#)

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### [PDF] TEST AND REPAIR OF NON-VOLATILE COMMODITY AND EMBEDDED MEMORIES

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... memory **tester** may be required to access embedded **Flash** through logic pins. ... However, it is getting more difficult for **ATE** maker to design one **tester** fits all ...

[csdl.computer.org/comp/proceedings/itc/2002/7543/00/75431223.pdf](http://csdl.computer.org/comp/proceedings/itc/2002/7543/00/75431223.pdf) - [Similar pages](#)

### [PDF] SELECTIVE OPTIMIZATION OF TEST FOR EMBEDDED FLASH MEMORY

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... memory is a poor candidate for **BIST** analysis and ... Testing embedded **Flash** usually means that a relatively costly logic or mixed signal **tester** will be ...

[csdl.computer.org/comp/proceedings/itc/2002/7543/00/75431222.pdf](http://csdl.computer.org/comp/proceedings/itc/2002/7543/00/75431222.pdf) - [Similar pages](#)

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### Chip Scale Review Magazine

... Due to the various types of die that may be included in an MCP (**flash**, SRAM, or DRAM memory), older existing **ATE** can be used." ... The Credence Kalos 2 **Tester**. ...

[www.chipscalereview.com/current/article.php?type=feature&article=f2](http://www.chipscalereview.com/current/article.php?type=feature&article=f2) - 29k - [Cached](#) - [Similar pages](#)

### [PDF] Toward Embedded Memory Self-Repair

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... requirement Speed discrepancy between the **ATE** and the ... Soft repair mechanism Only logic **tester** is needed ... repair Non-volatile repair storage **Flash** memory, **EEPROM** ...

[larc.ee.nthu.edu.tw/dtc/doc/bisr-cthuang-bw](http://larc.ee.nthu.edu.tw/dtc/doc/bisr-cthuang-bw) - [Similar pages](#)

### EEProductCenter.com :: BIST targets GHz-speed serial I/O

... From consulting on **tester** capabilities, the company is gradually ... external active subsystems, just as **ATE** may no ... and in-system programming of **flash** memories and ...

[www.eeproductcenter.com/test-measure/focuson/showArticle.jhtml?articleID=18902491](http://www.eeproductcenter.com/test-measure/focuson/showArticle.jhtml?articleID=18902491) - 26k - [Cached](#) - [Similar pages](#)

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EEProductCenter.com :: Production **tester** addresses high-speed ...

... of both worlds: the fault coverage of **ATE**, at the low ... With **BIST** Assist, an Agilent 93000 **tester** for PCI ... testing and in-system programming of **flash** memories and ...  
www.eeproductcenter.com/test-measure/brief/showArticle.jhtml?articleID=19201911 - 25k -  
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FPGA Configuration, **BIST**, **FLASH** programming, system test, gang ...

... IP can execute deterministic embedded test at anytime and anywhere without the need to be connected to **ATE**; TEST-IP reduces in-system **FLASH** programming times; ...  
www.intellitech.com/products/testipfamily.asp - 12k - Jun 8, 2004 - [Cached](#) - [Similar pages](#)

FPGA Configuration, **BIST**, **FLASH** programming, system test, gang ...

... such as FPGAs, CPLDs, and non-volatile **EEPROM** and **FLASH** ... eg, stored in the CPU's **FLASH** memory). ... that is automatically understood by external **ATE**, is needed. ...  
www.intellitech.com/technologies/infrastructureip.asp - 17k - [Cached](#) - [Similar pages](#)  
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